Hyper Suprime-Cam

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HSC Components

- HSC Mechanics (telescope interface)
- Wide Field Corrector
- HSC Camera Mechanics
 - Dewar
 - Shutter
 - Filter Exchanger
- Sensor
 - · CCD
 - Electronics
- Filter
- SH (mirror analysis) & Guider
- Data management

Mitsubishi Canon

NAOJ U-Tokyo KEK Princeton ASIAA

Hyper Suprime-Cam

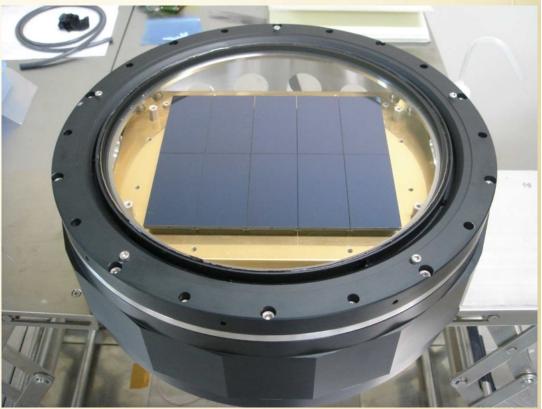
Primary Technical Specifications

Field of View	15 degree diameter	Vignetting allowed up to 25 % at the edge Dead area (CCD gap) fraction ≤ 5 %
Instrument PSF size	≤ 0 ".3 for r', i'	FWHM
Pixel scale	$\leq 0^n.4$ for g', Y $\leq 0^n.2$ /pix	
System Throughput	> 50 % for g'	PM×WFC×Filter×CCD
	≥ 65 % for r'	at the center of the field
	≥ 65 % for i'	
	≥ 40 % for z'	
	≥ X % for Y	
Minimum Shutter Speed	3 sec (1 sec goal)	Time accuracy ≤ ⊥ 1 %
Min. interval of Exposures	20 sec (15 sec goal)	Including CCD readout and wipe pointing change

Hamamatsu CCD



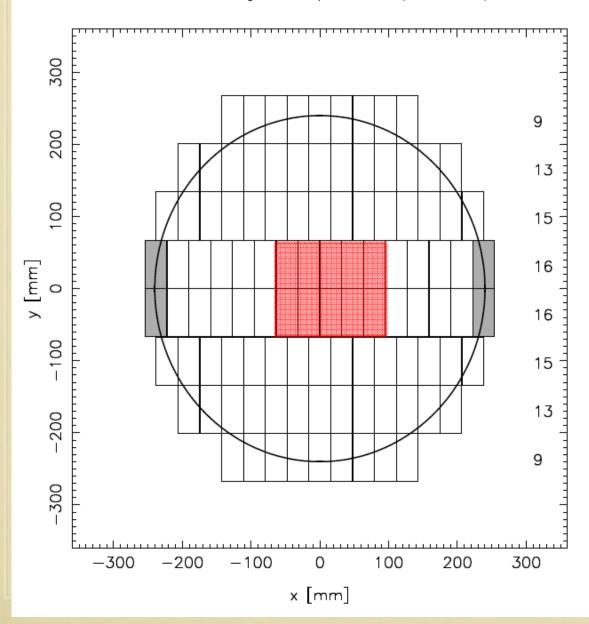
2048 x 4096 15 micron four side buttable



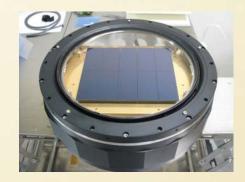
Suprime-Cam CCDs will be replaced and the commissioning run is 2008/06

HSC: Focal Plane

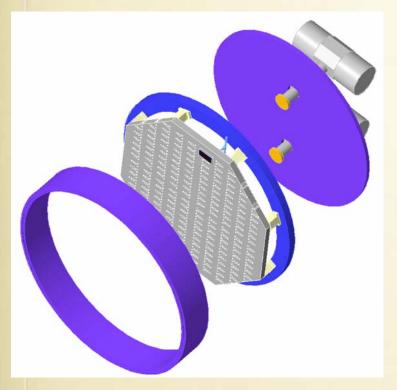
HSC CCD alignment, pattern 2 (106 CCDs)



106 2k4kFDCCD



HSC: Focal Plane







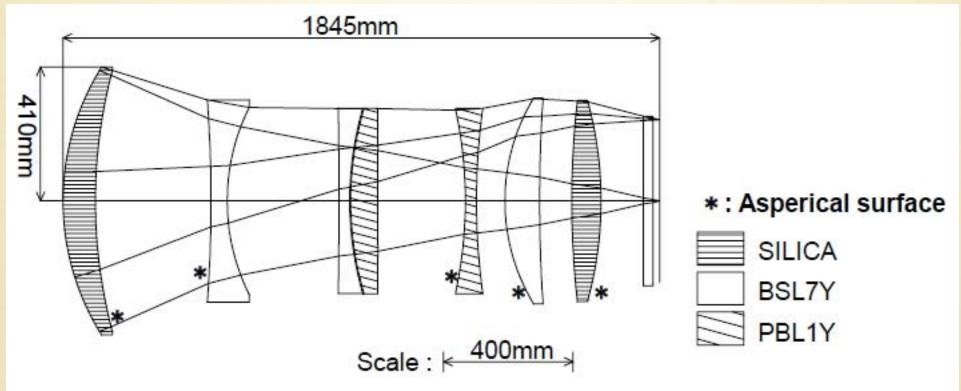
GAIA demo model 77 x 58 x 3.8 cm

 $P_{input} \sim 65W$ $P_{rad} \sim 50W$ Pulse Tube x 2 Fuji Electric 48 W @ -100C

SiC Focal Plane
CTE: 3.7 ppm
close to AIN

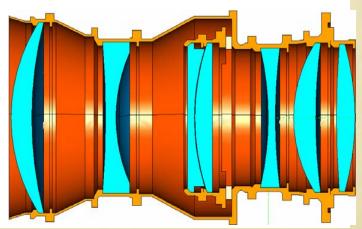
TC: 200 W/mK YM: high enough

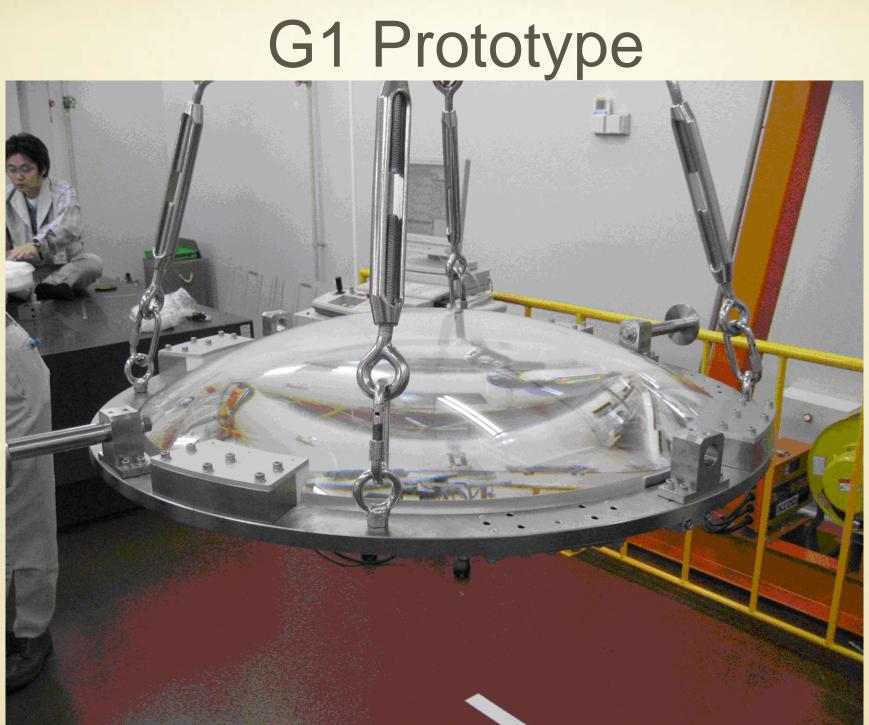
Wide Field Corrector



General Lens Data

Focal length	18416[mm]	
image scale	0.0893[mm/arcsec]	
image size	ϕ 498[mm]	





Broad band Filter

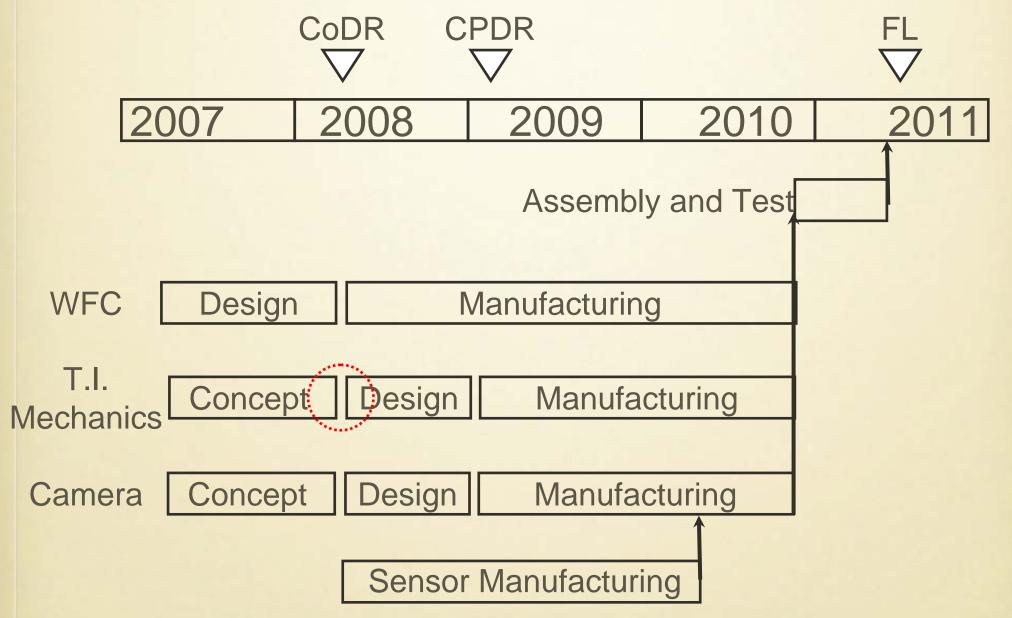
Prototype delivered on 2008/02/29



All the spec met at high level

Uniformity: cutoff 3 nm transmission 2-3 %

HSC Schedule



Summary

- CCD and WFC development is on schedule.
- Conceptual study of HSC mechanics is behind schedule by ~ 6 month because of the significant change of the configuration.
- Prototyping of the filters are underway. Final spec. depends on the result of prototyping.
- Impact assessments are important.